

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10571279	TAKAHASHI ET AL.
Examiner	Art Unit	
Loewe, Sun Jae Y	1626	

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
restriction requirement	1-4-2008	sl
stn: registry & caplus	3-18-2008	sl
palm all inventors	3-18-2008	sl

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner